

<b>Notice of References Cited</b>	Application/Control No. 10/783,783		Applicant(s)/Patent Under Reexamination KLENK ET AL.	
	Examiner DIANE YABUT		Art Unit 3734	Page 1 of 1

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*	B	US-6,537,299	03-2003	Hogendijk et al.	606/213
*	C	US-6,592,593	07-2003	Parodi et al.	606/108
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	M	US-			

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**NON-PATENT DOCUMENTS**

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